S	Sear	rch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/028,825	YAMASAKI ET AL.
Examiner	Art Unit
Mai T. Tran	2129

SEARCHED				
Class	Subclass	Date	Examiner	
706	47	3/4/2006	mtt	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

(INCLUDING SEARCH	SIRAIEGY)
	DATE	EXMR
EAST (Please see search history printout)	3/4/2006	mtt
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